
M P Seah, Nuclear Instruments and Methods B 239 (2005) 286-287
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In the publication of the new general, predictive semi-empirical equation for the sputtering yields of mono-elemental solids, using 250 eV to 10000 eV ions incident normally on the surface [1], two curves had incorrectly labeled primary ion energies. This report clarifies the relevant Figs. This overall approach gives accuracies around 10% for inert gas sputter yields for elemental samples.

The corrected plots are shown in Fig. 1.

![Corrected plots for Neon and Xenon](image_url)

Fig 1 The predicted sputtering yields for Ne (left) and Xe (right) for 1 and 5 keV ions. Figs 7, 8 and 9 in reference [1] showed 1 and 100 keV, rather than 1 and 5 keV as labeled.

Detailed plots of the predictions and a series of tables for the yields for Ne, Ar and Xe, for 0° and 45° angles of incidence, are provided on the NPL web site. These may be found by using the links on the home page to this web site [2].